



# Spectroscopic diagnostics for upper divertor and central stack on NSTX-U

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# Abstract

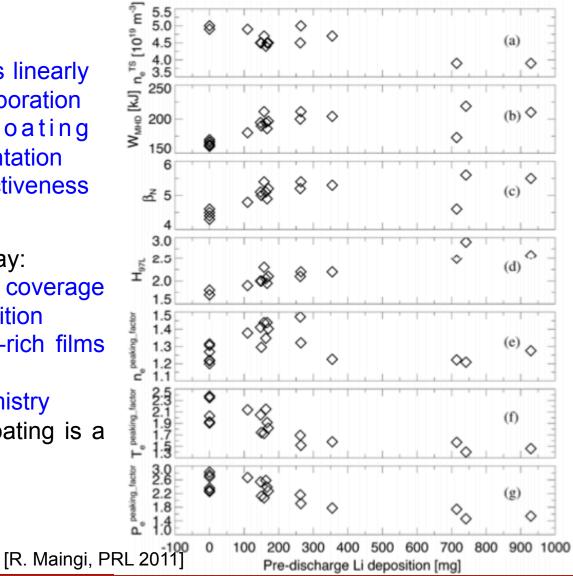
NSTX has demonstrated a number of discharge characteristics that improved with increasing lithium coatings, all with nominal thickness >> ion implantation depth. The asymmetries in the lithium coating and erosion and re-deposition of lithium in other regions possibly explain this phenomenon. In order to investigate the role of these mechanisms, new high resolution UV-VIS-NIR spectroscopic diagnostics are to be installed in NSTX-U to monitor the previously uncovered upper divertor and central stack region. The diagnostics consist of a high speed ProEM-HS 512 camera, an IsoPlane SCT320 spectrometer and 32 sightlines: 16 sightlines on the upper divertor and 16 sightlines on the central stack. The ratio of lithium emission to carbon emission as a function of pre-discharge lithium deposition will be measured in these two region to evaluate the hypothesis.

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Valuable discussions with V. A. Soukhanovskii are gratefully acknowledged

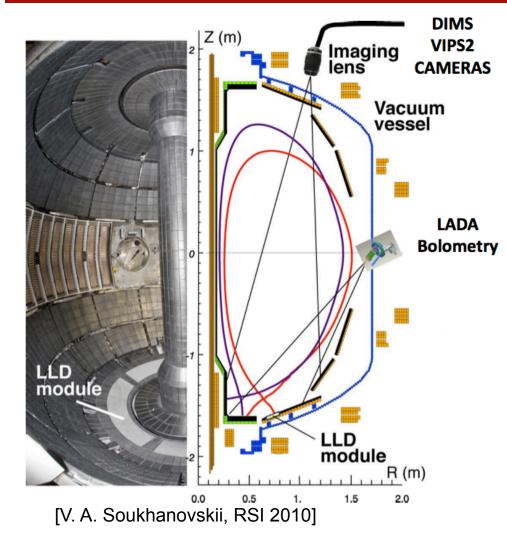
### Motivation: understanding Li coating effectiveness

- Open question:
  - Improvement increases linearly with pre-discharge evaporation
  - But... Nominal coating thickness >> ion implantation
  - What governs the effectiveness of Li deposition?
  - Possible mechanism at play:
    - Role of regions low Li coverage
    - Erosion and re-deposition
    - Deposition of carbon-rich films during discharge
    - Lithium-Carbon chemistry
  - Spatial distribution of Li coating is a key element





### Lower divertor was well diagnosed on NSTX

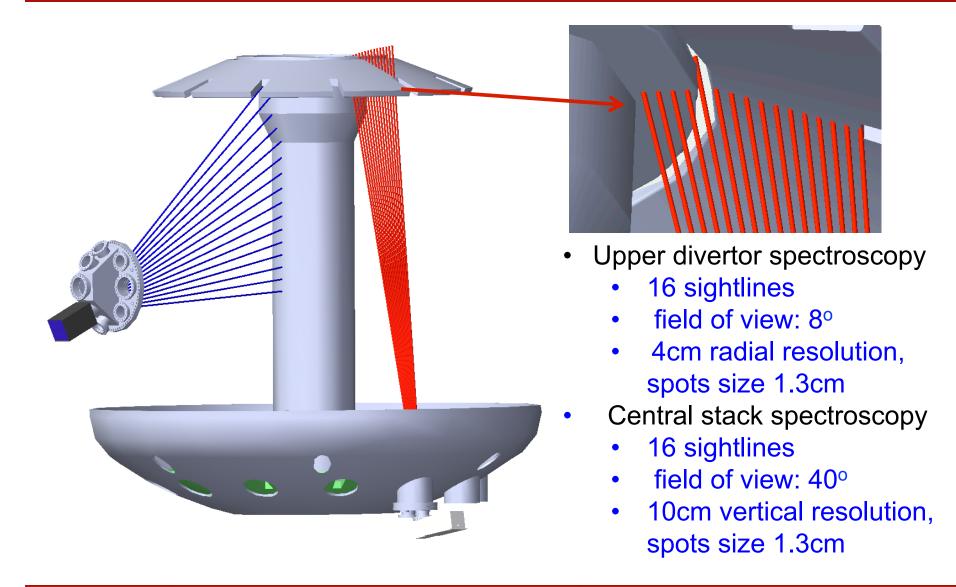


- Multi channel spectrometers (DIMS/VIPS2, LLNL/PPPL)
  - UV-VIS-NIR range, high resolution
  - 48 chords (30 simultaneously)
- Single channel spectrometers (ORNL)
   4X, VIS-UV, low resolution
- Diodes array (LADA/filter-scopes)
  - Lyα, Dα, C III, Li I
- Visible cameras (1D/2D)
  - Li I, Li II, C II, C III
  - IR cameras (ORNL)
    - Fast dual band (L/MWIR, 1.6 kHz)
    - Wide angle (180° divertor coverage)

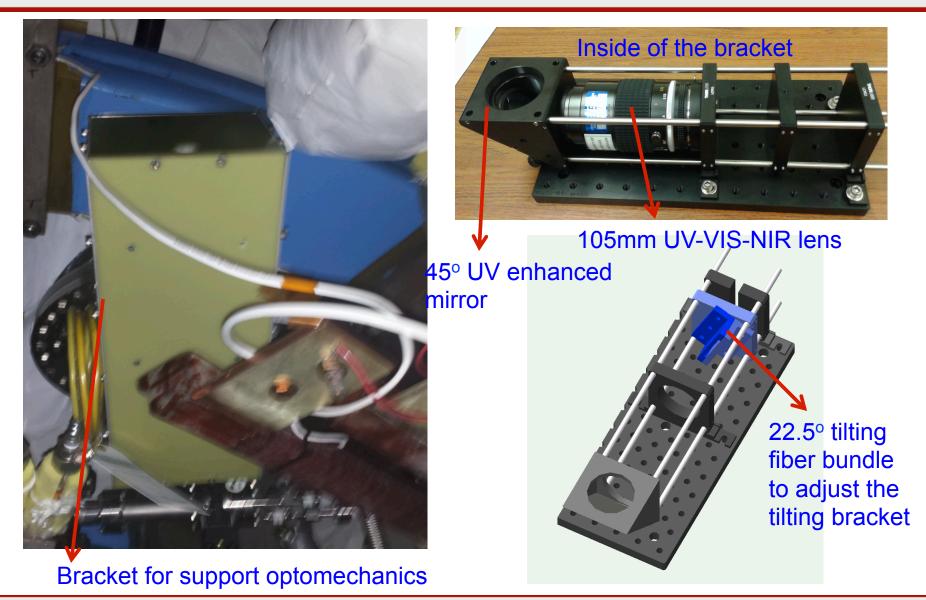
### Poor coverage of the central stack and upper divertor



### New spectroscopy Diagnostics port allocation

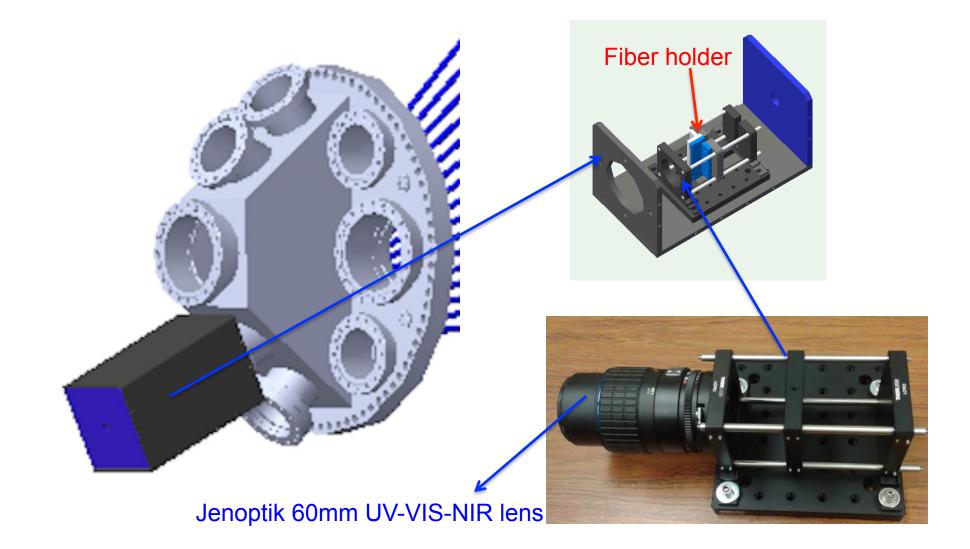


### The optomechanics for Upper divertor spectroscopy





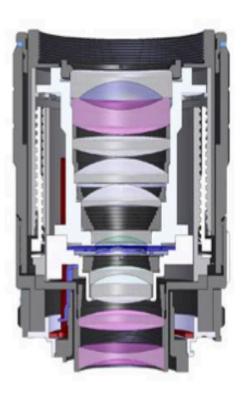
### The optomechanics for Central stack spectroscopy





## Jenopitik 60mm lens

- No focus shift from UV thru IR
- Excellent UV transmission
- Flare and ghosting minimized across the UV–IR spectrum with advanced ultra broadband AR coatings
- Automatic diaphragm for maximum viewfinder brightness
- Precision manual focus with long life all-metal construction
- Advanced floating element design including five calcium fluoride elements ensures stunning performance in all conditions

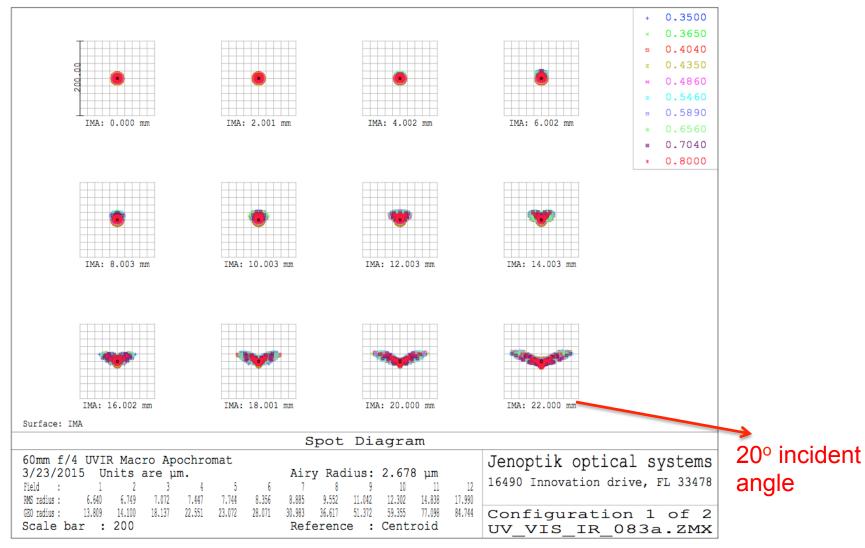


Focal Length: 60mm Aperture Range: f/4 - f/45 No. of Elements/Groups: 10/9 Maximum Format Size: 24 x 36mm Transmission Wavebang: 290 – 1500nm Apochromatic Waveband: 315 – 1100nm Focus Range: 264mm (10.4in) – Infinity Maximum Magnification: 1:1.5 Mounting Flange: Nikon F Mount Filter:  $\mathbf{52}$ mm thread (M 52 x 0.75) Weight: 535g (1.18lb) Length: 73.4mm (2.7in)

The height is 44mm for fiber array on the focal plane

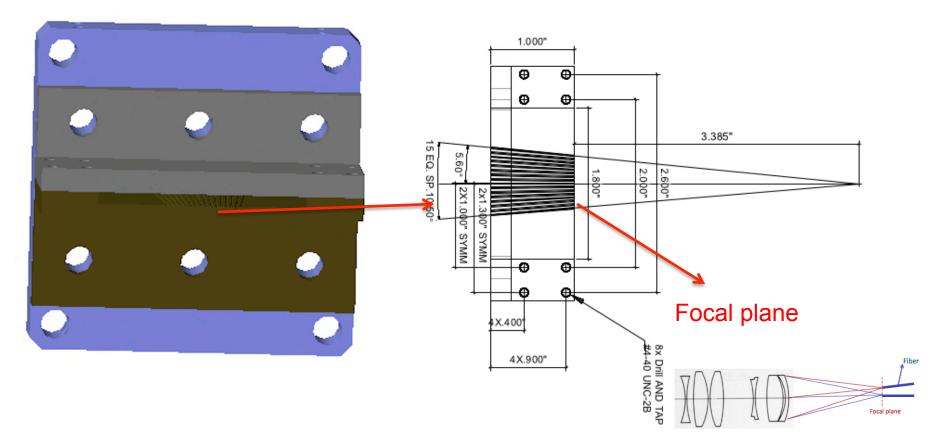


### Spot diagram for 60mm Lens



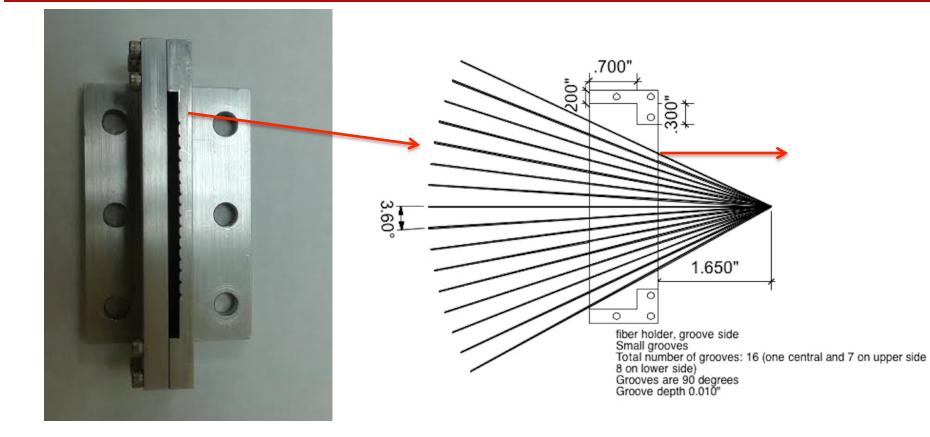
The image is good for 480nm fiber under 20° incident angle

### Fiber holder design for upper divertor spectroscopy



- Each fiber will tilt toward to the point which is 3.385" far away form the focal plane. The 3.385" is measured ( to keep each fiber acquire the same intensity of signal.
- The 3.385" is the same distance between the focal plane and the lens

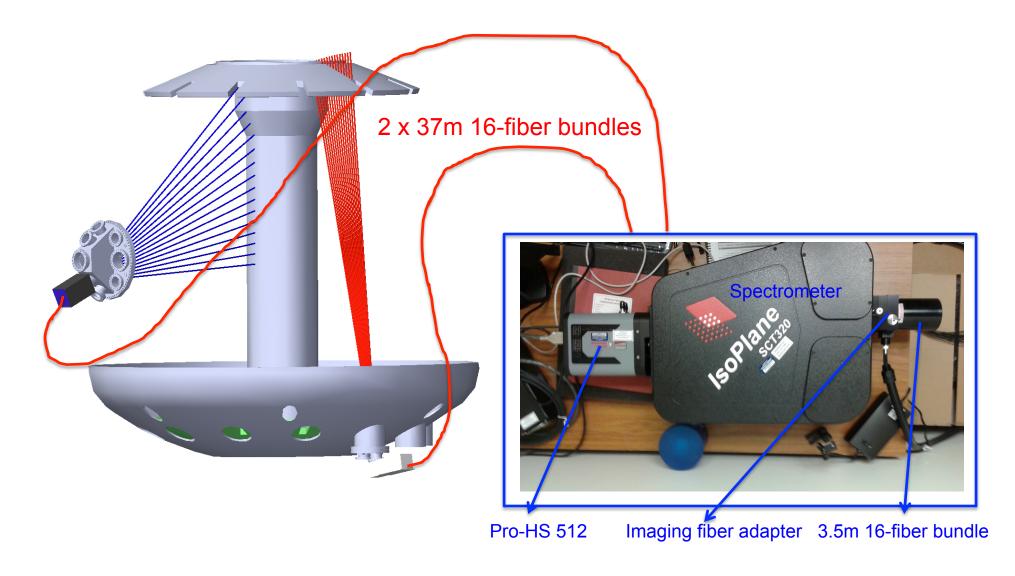
### Fiber holder design for central stack spectroscopy



### 1.650" is the distance between the lens and the focal plane.



# Camera and spectrometer will be in remote room shielded from radiation



## Princeton Instruments ProEM-HS:512B X 3

FEATURES	BENEFITS				
Patented eXcelon <sup>®</sup> 3 technology	Enhanced QE and fringe suppression versus standard back illuminated sensors.				
20 MHz/16-bit readout	61 fps rate at full-frame resolution. Use ROI/binning for hundreds of frames per second.				
All-metal, hermetic vacuum design	Lifetime vacuum guarantee and deep cooling. No epoxies used. Lowest dark current.				
OptiCAL	Linear, absolute EM gain calibration using built in precision light source. EM and Non-EM modes for the lowest noise and the best linearity.				
BASE	Baseline Active Stability Engine - stable reference for quantitative measurements.				
High speed CCD readout	>1000 fps with reduced ROI size, >10,000 fps in spectroscopy mode.				
100 kHz/16-bit readout	Noise performance of a slow scan camera for precise photometry applications.				
Single optical window	Vacuum window is the only optical surface between incident light and the CCD surface; Advanced AR coatings for the highest throughput.				
Built-in shutter	Conveniently capture dark reference frames and protect camera from dust when not in use.				
Flexible lens mounts	C-mount (standard), Canon mount and adjustable C-to-Spectroscope mount - easily attaches to microscopes, standard lenses, telescopes or other optical instruments.				
Gigabit Ethernet (GigE) interface	Industry standard for fast data transfer over long distances, up to 50m. Extenders available for even greater distance.				
<b>Optional:</b> LightField <sup>®</sup> (for Windows 8/7, 64-bit)	Flexible software packages for data acquisition, display and analysis;				
Or WinView/Spec (for Windows 8/7/XP, 32-bit)	LightField offers intuitive, cutting edge user interface, IntelliCal <sup>®</sup> and more.				
PICAM (64-bit) / PVCAM (32-bit)	Compatible with Windows 8/7/XP, and Linux;				
software development kits (SDKs)	Universal programming interfaces for easy custom programming.				
LabVIEW®	Easy integration of camera into complex experiments.				
LabVIEW®	Easy integration of camera into complex experiments.				

### Princeton Instruments ProEM-HS:512B X 3

	ProEM-HS: 512BX3						
Sensor	Back-illuminated 512 x 512 eXcelon3 EMCC						
Shutter	25 mm shutter included	5 mm shutter included					
	EM mode	Normal CCD mode					
Read noise	25 e <sup>-</sup> rms @ 5 MHz 50 e <sup>-</sup> rms @ 10 MHz 120 e <sup>-</sup> rms @ 20 MHz Read noise effectively reduced to <1 e <sup>-</sup> rms with on-chip multiplication gain enabled	3 e <sup>-</sup> rms @ 100 kHz 4.9 e <sup>-</sup> rms @ 1 MHz					
Non-Linearity	<2%	<1%					
Analog gain	12, 6, 3 e-/ADU	3.2, 1.6, 0.8 e-/ADU					
Full well EM mode only EM and Normal CCD modes	800 ke <sup>-</sup> (output amplifier) 200 ke <sup>-</sup> (single pixel)						
Deepest cooling temperature* (@ +20° C ambient; 10 MHz ADC)	-70° C +/- 0.05° C (guaranteed) Maximum Cooling: -80° C (air), -85° C (+2	0° C liquid), -90° C (+10° C liquid)					
Dark current	0.001 e-/p/sec (typical), 0.02 e-/p/sec (mc	ximum)					
Clock induced charge (CIC) Measured at 1000x EM Gain	0.002 e-/pixel/frame						
Electron multiplication (EM) gain	1 to 1000x, controlled in linear, absolute ste	ps 🛞 70					
Digitization	16 bits @ 20 MHz, 10 MHz, 5 MHz, 1 MHz	ps and 100 kHz					
Vertical shift rate	300 nsec/row - 5 µsec/row (variable)						
Operating systems supported	Windows 8/7 (64-bit) and Linux (64-bit), Windo	ows 8/7/XP (32-bit)					
I/O signals	Exposure, Readout, Trigger In, Image Shift, V	Vaiting for Trigger					
Operating environment	0 to $30^\circ$ C ambient, 0 to $80\%$ relative humic	lity, non-condensing	500 600 700 800 900 1000 1100				
Certification	CE		Wavelength (nm) eXcelon3 EMCCD Optional UV coating				
Dimensions / Weight	8.02 inches (20.37 cm) x 5.8 inches (14.73 cm) x Approximately 9.2 lbs (4.2 kg)	x 5.8 inches (14.73 cm) L x W x H					



### Princeton Instruments ProEM-HS:512B X 3

### Frame Rates (Standard Mode)

Binning	512 x 512	256 x 256	128 x 128	64 x 64	32 x 32
1 x 1	61	120	228	416	711
2 x 2	120	228	416	711	1099
4 x 4	228	416	711	1099	1506
8 x 8	416	711	1099	1506	1851

#### Frame Rates (High Speed CCD Readout Mode)

### (High Speed Spectroscopy Readout Mode)

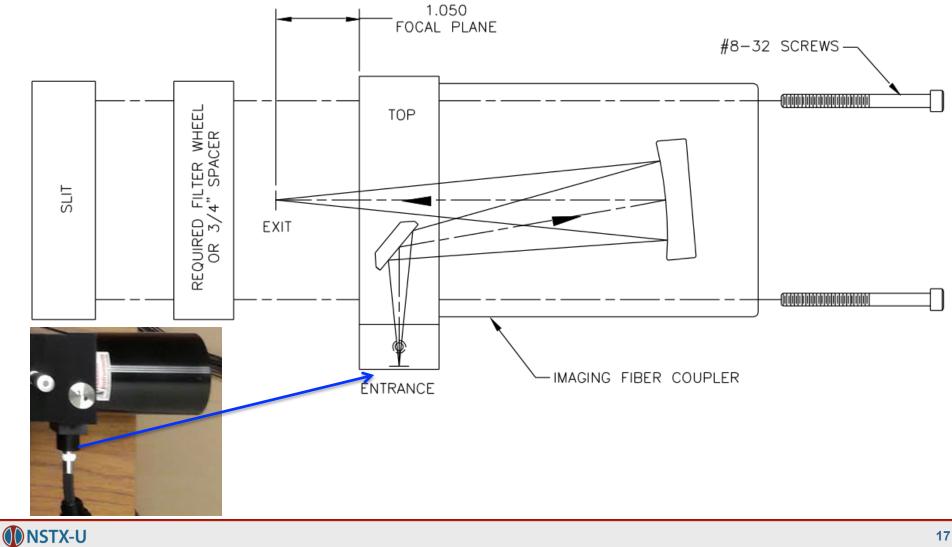
Binning	512 x 512	256 x 172	92 x 101	64 x 62	32 x 30	Binning	512 x 100	512 x 32	512 x 1
1 x 1	61	201.6	865	1529	3472	1 x 100	13850		
2 x 2	120	381	1557	2652	5617	1 x 32		19305	
4 x 4	228	682	2645	4132	7490	1 x 1			23529
8 x 8	416	1131	3968	5899	9708				

### IsoPlane SCT 320 spectrometer

	IsoPlane SCT 320				
Focal length	320 mm				
Aperture ratio	f/4.6				
Scan range (with 1200 g/mm grating at 435 nm)	0 - 1400 nm				
Linear dispersion	2.38 nm/mm				
CCD resolution (20 µm pixel, 10 µm slit width)	0.08 nm				
PMT resolution (10 $\mu m$ slit, 4 mm high, 1200 g/mm grating at 435 nm)	0.05 nm				
Wavelength coverage	64 nm				
Grating size	68 x 68 mm				
Grating mount	Interchangeable triple grating turret				
Focal plane size	27 mm wide x 14 mm high *				
Astigmatism	Zero ( 0 )				
Coma	Corrected at 500 nm with 1200 g/mm grating				
Slits	Manual (10 µm to 3 mm) or optional motorized or kinematic entrance slits; Optional manual or motorized exit slits				
Wavelength accuracy	± 0.2 nm				
Repeatability	± 0.05 nm				
Drive step size	0.005 nm				
Size	20.4 in (518 mm) long 17.7 in (450 mm) wide 8.5 in (216 mm) high				
Optical axis height	4.875 in (124 mm) with rubber feet 4.313 in (110 mm) without rubber feet				
Weight	~ 60 lbs [27 kg]				
Computer interface	USB and RS232				

Two grating, 2400gr/mm and 3600gr/mm have been installed in this spectrometer

## Imaging fiber adapter



### Fiber bundles



2 X 37m 16-fibers bundles



1 X 3.5m 16-fiber bundle

- Fiber: Polymicro FBP400440480
- Diameter: 480nm
- full acceptance angle: 25.4°
- Low Loss Broad Spectrum Fiber, 275-2100nm Recommended bend radius: 74.2mm
- Each fiber has been jacked with Hytrel
- The Fiber is the same as NSTX-U DIMS system



## Summary

The fiber bundles, spectrometer and the camera have been prepared for the upper divertor and central stack spectroscopy. Once the fiber holder for upper divertor view and bracket for central stack view are completed, the new high resolution UV-VIS-NIR spectroscopic diagnostics can be installed for NSTX-U to monitor the previously uncovered upper divertor and central stack region.